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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)

Complete if Known

Application Number	10/723,331
Filing Date	November 26, 2003
First Named Inventor	Liaw
Art Unit	TBD
Examiner Name	TBD
Attorney Docket Number	TSM03-1154

Sheet 1 of 1

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
<input checked="" type="checkbox"/>	A	US-6,643,167 B2	11-04-2003	Nil	
		US-			
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FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ¹
		Country Code ³ - Number ⁴ - Kind Code ⁵ (if known)				

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
<input checked="" type="checkbox"/>	B	DEGALAHAL, V., et al., "Analyzing Soft Errors in Leakage Optimized SRAM Design," Proc. Of 16 th International Conference on VLSI Design (January 2003) pp. 227-233.	
<input checked="" type="checkbox"/>	C	OSADA, K., et al., "Cosmic-Ray Multi-Error Immunity for SRAM, Based on Analysis of the Parasitic Bipolar Effect," 2003 Symposium on VLSI Circuits Digest of Technical Papers (June 2003) pp. 1-4.	

Examiner Signature	Date Considered
<i>[Signature]</i>	7-18-05

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